

# 4.5A Dual MOSFET Driver with Low Threshold Input and Enable

### Features

- High Peak Output Current: 4.5A (typical)
- Wide Input Supply Voltage Operating Range:
   4.5V to 18V
- Low Shoot-Through/Cross-Conduction Current in Output Stage
- High Capacitive Load Drive Capability:
- 2200 pF in 12 ns (typical)
- Short Delay Times: 16 ns ( $t_{D1}$ ), 19 ns ( $t_{D2}$ ) (typical)
- Low Supply Current: 620 µA (typical)
- Low-Voltage Threshold Input and Enable with Hysteresis
- Latch-Up Protected: Withstands 500 mA Reverse Current
- Space-Saving Packages:
  - 8-Lead MSOP
  - 8-Lead SOIC
  - 8-Lead 2 x 3 TDFN

# Applications

- Switch Mode Power Supplies
- Pulse Transformer Drive
- Line Drivers
- Level Translator
- Motor and Solenoid Drive

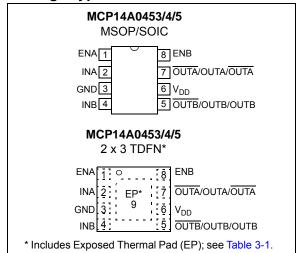
### **General Description**

The MCP14A0453/4/5 devices are high-speed dual MOSFET drivers that are capable of providing up to 4.5A of peak current while operating from a single 4.5V to 18V supply. There are three output configurations available: dual inverting (MCP14A0453), dual noninverting (MCP14A0454) and complementary (MCP14A0455). These devices feature low shoot-through current, matched rise and fall times, and short propagation delays, which make them ideal for high switching frequency applications.

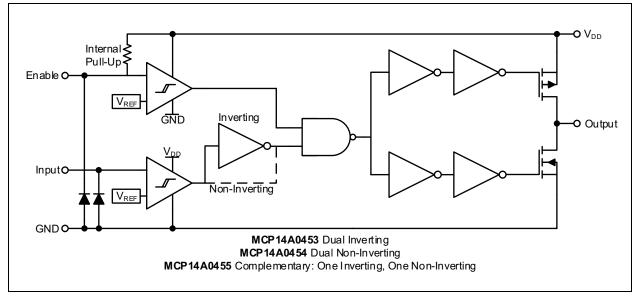
The MCP14A0453/4/5 family of devices offers enhanced control with Enable functionality. The active-high Enable pins can be driven low to drive the corresponding outputs of the MCP14A0453/4/5 low, regardless of the status of the Input pins. Integrated pull-up resistors allow the user to leave the Enable pins floating for standard operation.

These devices are highly latch-up resistant under any condition within their power and voltage ratings. They can accept up to 500 mA of reverse current being forced back into their outputs without damage or logic upset. All terminals are fully protected against electrostatic discharge (ESD) up to 2 kV (HBM) and 200V (MM).

# Package Types



# Functional Block Diagram



# 1.0 ELECTRICAL CHARACTERISTICS

# 1.1 Electrical Specifications

# Absolute Maximum Ratings †

V <sub>DD</sub> , Supply Voltage	+20V
V <sub>IN</sub> , Input Voltage	(V <sub>DD</sub> + 0.3V) to (GND – 0.3V)
V <sub>EN</sub> , Enable Voltage	(V <sub>DD</sub> + 0.3V) to (GND – 0.3V)
Package Power Dissipation (T <sub>A</sub> = +50°C)	
8L MSOP	0.63W
8L SOIC	
8L 2 X 3 TDFN	
ESD protection on all pins	
ESD protection on all pins	

**† Notice:** Stresses above those listed under "Maximum ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at those or any other conditions above those indicated in the operational listings of this specification is not implied. Exposure to maximum rating conditions for extended periods may affect device reliability.

# TABLE 1-1: DC CHARACTERISTICS

Electrical Specifications: Unle	1	e noted, $I_A =$	1	with $4.5V \leq V$		
Parameters	Sym.	Min.	Тур.	Max.	Units	Conditions
Input						
Input Voltage Range	V <sub>IN</sub>	GND – 0.3V	_	V <sub>DD</sub> + 0.3	V	
Logic '1' High Input Voltage	V <sub>IH</sub>	2.0	1.6	—	V	
Logic '0' Low Input Voltage	V <sub>IL</sub>	—	1.3	0.8	V	
Input Voltage Hysteresis	V <sub>HYST(IN)</sub>	—	0.3	—	V	
Input Current	I <sub>IN</sub>	-1		+1	μA	$0V \le V_{IN} \le V_{DD}$
Enable						•
Enable Voltage Range	V <sub>EN</sub>	GND – 0.3V	_	V <sub>DD</sub> + 0.3	V	
Logic '1' High Enable Voltage	V <sub>EH</sub>	2.0	1.6	—	V	
Logic '0' Low Enable Voltage	V <sub>EL</sub>	—	1.3	0.8	V	
Enable Voltage Hysteresis	V <sub>HYST(EN)</sub>	_	0.3	_	V	
Enable Pin Pull-Up Resistance	R <sub>ENBL</sub>		1.5	_	MΩ	V <sub>DD</sub> = 18V, ENB = A <sub>GND</sub>
Enable Input Current	I <sub>EN</sub>	_	12	_	μA	$V_{DD} = 18V$ , ENB = $A_{GND}$
Propagation Delay	t <sub>D3</sub>	_	16	23	ns	V <sub>DD</sub> = 18V, V <sub>EN</sub> = 5V, see Figure 4-3, ( <b>Note 1</b> )
Propagation Delay	t <sub>D4</sub>	—	19	26	ns	V <sub>DD</sub> = 18V, V <sub>EN</sub> = 5V, see Figure 4-3, ( <b>Note 1</b> )
Output						
High Output Voltage	V <sub>OH</sub>	V <sub>DD</sub> – 0.025		_	V	I <sub>OUT</sub> = 0A
Low Output Voltage	V <sub>OL</sub>		_	0.025	V	I <sub>OUT</sub> = 0A
Output Resistance, High	R <sub>OH</sub>		1.7	2.7	Ω	I <sub>OUT</sub> = 10 mA, V <sub>DD</sub> = 18V
Output Resistance, Low	R <sub>OL</sub>		1.3	2.3	Ω	I <sub>OUT</sub> = 10 mA, V <sub>DD</sub> = 18V
Peak Output Current	I <sub>PK</sub>		4.5	_	Α	V <sub>DD</sub> = 18V (Note 1)
Latch-Up Protection Withstand Reverse Current	I <sub>REV</sub>	0.5	_		A	Duty cycle ≤ 2%, t ≤ 300 µs (Note 1)
Switching Time (Note 1)						
Rise Time	t <sub>R</sub>	—	12	17	ns	V <sub>DD</sub> = 18V, C <sub>L</sub> = 1800 pF, see Figure 4-1, Figure 4-2
Fall Time	t <sub>F</sub>	—	12	17	ns	$V_{DD}$ = 18V, C <sub>L</sub> = 1800 pF, see Figure 4-1, Figure 4-2
Delay Time	t <sub>D1</sub>	-	16	23	ns	$V_{DD} = 18V, V_{IN} = 5V,$ see Figure 4-1, Figure 4-2
	t <sub>D2</sub>	_	19	26	ns	$V_{DD} = 18V, V_{IN} = 5V,$ see Figure 4-1, Figure 4-2
Power Supply	1			I	1	
Supply Voltage	V <sub>DD</sub>	4.5	_	18	V	
	I <sub>DD</sub>		620	900	μA	V <sub>INA/B</sub> = 3V, V <sub>ENA/B</sub> = 3V
			620	900	μΑ	$V_{\text{INA/B}} = 0V, V_{\text{ENA/B}} = 3V$
Power Supply Current		_	620	900		$V_{\text{INA/B}} = 3V, V_{\text{ENA/B}} = 3V$
	I <sub>DD</sub>		620	900	μΑ	
Note 1: Tested during charac	I <sub>DD</sub>			900	μA	$V_{INA/B} = 0V, V_{ENA/B} = 0V$

**Note 1:** Tested during characterization, not production tested.

<b>Electrical Specifications:</b> Unless otherwise indicated, over the operating range with $4.5V \le V_{DD} \le 18V$ .								
Parameters	Sym.	Min.	Тур.	Max.	Unit s	Conditions		
Input								
Input Voltage Range	V <sub>IN</sub>	GND – 0.3V	_	V <sub>DD</sub> + 0.3	V			
Logic '1' High Input Voltage	V <sub>IH</sub>	2.0	1.6	_	V			
Logic '0' Low Input Voltage	V <sub>IL</sub>	—	1.3	0.8	V			
Input Voltage Hysteresis	V <sub>HYST(IN)</sub>	—	0.3	_	V			
Input Current	I <sub>IN</sub>	-10	_	+10	μA	$0V \le V_{IN} \le V_{DD}$		
Enable								
Enable Voltage Range	V <sub>EN</sub>	GND – 0.3V		V <sub>DD</sub> + 0.3	V			
Logic '1' High Enable Voltage	V <sub>EH</sub>	2.0	1.6	_	V			
Logic '0' Low Enable Voltage	V <sub>EL</sub>	_	1.3	0.8	V			
Enable Voltage Hysteresis	V <sub>HYST(EN)</sub>	_	0.3	_	V			
Enable Input Current	I <sub>EN</sub>	_	12	_	μA	V <sub>DD</sub> = 18V, ENB = A <sub>GND</sub>		
Propagation Delay	t <sub>D3</sub>	—	20	27	ns	$V_{DD}$ = 18V, $V_{EN}$ = 5V, $T_A$ = +125°C, see Figure 4-3, ( <b>Note 1</b> )		
Propagation Delay	t <sub>D4</sub>	—	24	31	ns	$V_{DD}$ = 18V, $V_{EN}$ = 5V, $T_A$ = +125°C, see Figure 4-3, ( <b>Note 1</b> )		
Output								
High Output Voltage	V <sub>OH</sub>	V <sub>DD</sub> – 0.025	_	_	V	DC Test		
Low Output Voltage	V <sub>OL</sub>	_	—	0.025	V	DC Test		
Output Resistance, High	R <sub>OH</sub>	_	_	3.3	Ω	I <sub>OUT</sub> = 10 mA, V <sub>DD</sub> = 18V		
Output Resistance, Low	R <sub>OL</sub>	_	_	2.9	Ω	I <sub>OUT</sub> = 10 mA, V <sub>DD</sub> = 18V		

 TABLE 1-2:
 DC CHARACTERISTICS (OVER OPERATING TEMP. RANGE)

**Note 1:** Tested during characterization, not production tested.

# TABLE 1-2: DC CHARACTERISTICS (OVER OPERATING TEMP. RANGE) (CONTINUED)

<b>Electrical Specifications:</b> Onless otherwise indicated, over the operating range with $4.5v \le v_{DD} \le 18v$ .								
Parameters	Sym.	Min.	Тур.	Max.	Unit s	Conditions		
Switching Time (Note 1)								
Rise Time	t <sub>R</sub>	—	14	19	ns	$V_{DD} = 18V, C_{L} = 1800 \text{ pF},$ T <sub>A</sub> = +125°C, see Figure 4-1, Figure 4-2		
Fall Time	t <sub>F</sub>	—	14	19	ns	$V_{DD} = 18V, C_{L} = 1800 \text{ pF},$ T <sub>A</sub> = +125°C, see Figure 4-1, Figure 4-2		
Delay Time	t <sub>D1</sub>	—	20	27	ns	$V_{DD}$ = 18V, $V_{IN}$ = 5V, $T_A$ = +125°C, see Figure 4-1, Figure 4-2		
	t <sub>D2</sub>	—	24	31		$V_{DD}$ = 18V, $V_{IN}$ = 5V, $T_A$ = +125°C, see Figure 4-1, Figure 4-2		
Power Supply								
Supply Voltage	V <sub>DD</sub>	4.5	—	18	V			
	I <sub>DD</sub>	_	—	1100	μA	$V_{INA/B} = 3V, V_{ENA/B} = 3V$		
Power Supply Current	I <sub>DD</sub>	—	_	1100	μA	V <sub>INA/B</sub> = 0V, V <sub>ENA/B</sub> = 3V		
	I <sub>DD</sub>	_	—	1100	μA	$V_{INA/B} = 3V, V_{ENA/B} = 0V$		
	I <sub>DD</sub>		_	1100	μA	$V_{INA/B} = 0V, V_{ENA/B} = 0V$		

**Note 1:** Tested during characterization, not production tested.

### **1.2 Temperature Characteristics**

<b>Electrical Specifications:</b> Unless otherwise noted, all parameters apply with $4.5V \le V_{DD} \le 18V$								
Parameter	Sym.	Min.	Тур.	Max.	Units	Comments		
Temperature Ranges								
Specified Temperature Range	T <sub>A</sub>	-40	—	+125	°C			
Maximum Junction Temperature	TJ	_	_	+150	°C			
Storage Temperature Range	T <sub>A</sub>	-65	_	+150	°C			
Package Thermal Resistances								
Junction-to-Ambient Thermal Resistance, 8LD MSOP	$\theta_{JA}$		158		°C/W	Note 1		
Junction-to-Ambient Thermal Resistance, 8LD SOIC	$\theta_{JA}$	_	100	—	°C/W	Note 1		
Junction-to-Ambient Thermal Resistance, 8LD TDFN	$\theta_{JA}$	_	54	_	°C/W	Note 1		
Junction-to-Top Characterization Parameter, 8LD MSOP	$\Psi_{JT}$	_	2.4		°C/W	Note 1		
Junction-to-Top Characterization Parameter, 8LD SOIC	$\Psi_{JT}$	_	5.9	—	°C/W	Note 1		
Junction-to-Top Characterization Parameter, 8LD TDFN	$\Psi_{JT}$	_	0.5	—	°C/W	Note 1		
Junction-to-Board Characterization Parameter, 8LD MSOP	$\Psi_{JB}$	_	115	_	°C/W	Note 1		
Junction-to-Board Characterization Parameter, 8LD SOIC	$\Psi_{JB}$	_	65		°C/W	Note 1		
Junction-to-Board Characterization Parameter, 8LD TDFN	$\Psi_{JB}$	_	24		°C/W	Note 1		

**Note 1:** Parameter is determined using High K 2S2P 4-Layer board as described in JESD 51-7, as well as JESD 51-5 for packages with exposed pads.

#### 2.0 TYPICAL PERFORMANCE CURVES

Note: Unless otherwise indicated,  $T_A$  = +25°C with 4.5V  $\leq V_{DD} \leq$  18V.

Note: The graphs and tables provided following this note are a statistical summary based on a limited number of samples and are provided for informational purposes only. The performance characteristics listed herein are not tested or guaranteed. In some graphs or tables, the data presented may be outside the specified operating range (e.g., outside specified power supply range) and therefore outside the warranted range.

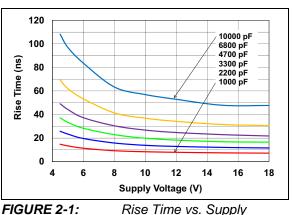


FIGURE 2-1: Voltage.

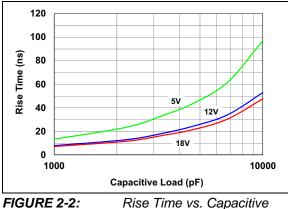
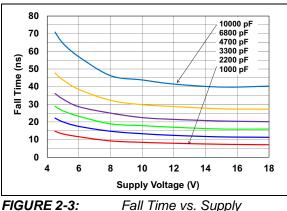


FIGURE 2-2: Load.



Voltage.

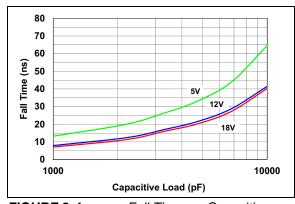


FIGURE 2-4: Fall Time vs. Capacitive Load.

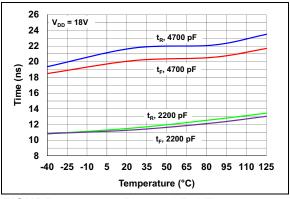
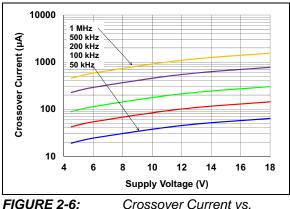


FIGURE 2-5: Rise and Fall Time vs. Temperature.



Supply Voltage.

Crossover Current vs.

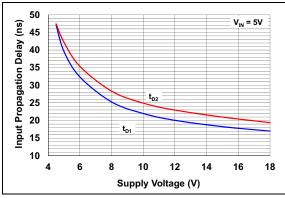


FIGURE 2-7: Input Propagation Delay vs. Supply Voltage.

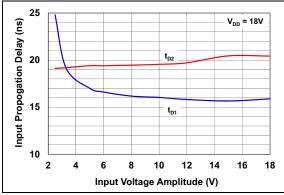


FIGURE 2-8: Input Propagation Delay Time vs. Input Amplitude.

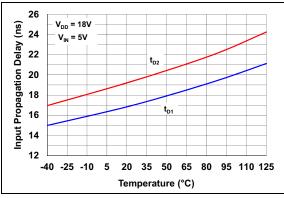
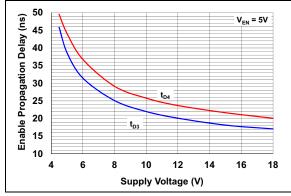
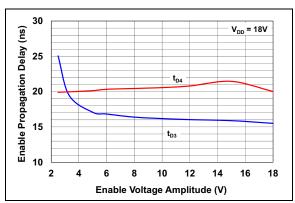


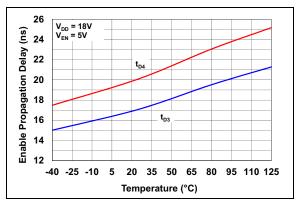
FIGURE 2-9: Input Propagation Delay vs. Temperature.



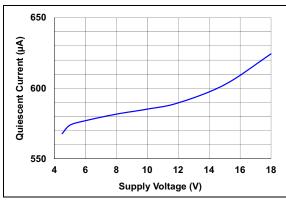
**FIGURE 2-10:** Enable Propagation Delay vs. Supply Voltage.

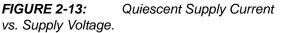


**FIGURE 2-11:** Enable Propagation Delay Time vs. Enable Voltage Amplitude.



**FIGURE 2-12:** Enable Propagation Delay vs. Temperature.





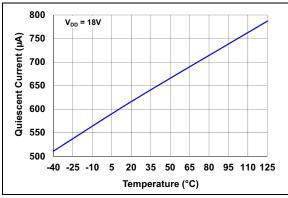


FIGURE 2-14: Quiescent Supply Current vs. Temperature.

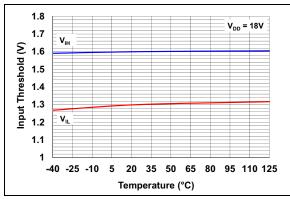


FIGURE 2-15: Input Threshold vs. Temperature.

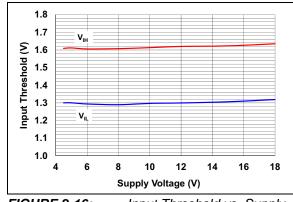
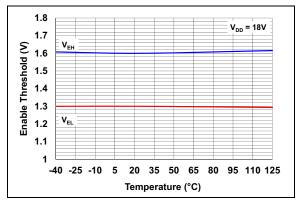


FIGURE 2-16: Input Threshold vs. Supply Voltage.



**FIGURE 2-17:** Enable Threshold vs. Temperature.

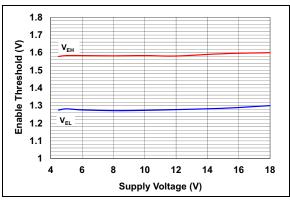


FIGURE 2-18: Enable Threshold vs. Supply Voltage.

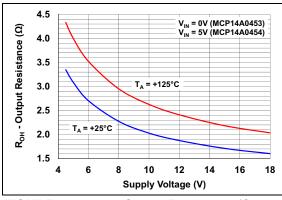


FIGURE 2-19: Output Resistance (Output High) vs. Supply Voltage.

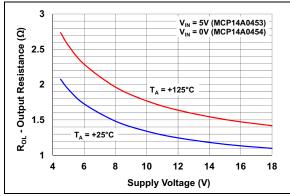


FIGURE 2-20: Output Resistance (Output Low) vs. Supply Voltage.

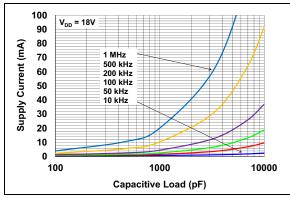
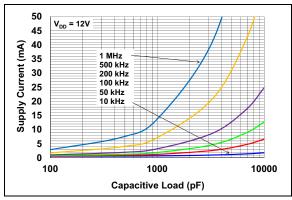
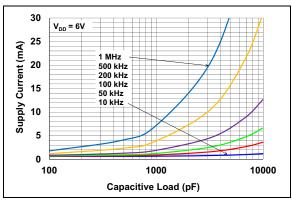


FIGURE 2-21: Supply Current vs. Capacitive Load ( $V_{DD} = 18V$ ).



**FIGURE 2-22:** Supply Current vs. Capacitive Load ( $V_{DD} = 12V$ ).



**FIGURE 2-23:** Supply Current vs. Capacitive Load ( $V_{DD} = 6V$ ).

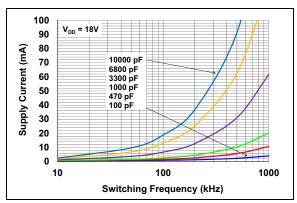


FIGURE 2-24: Supply Current vs. Frequency ( $V_{DD} = 18V$ ).

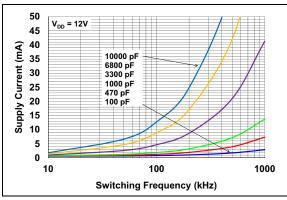


FIGURE 2-25: Supply Current vs. Frequency ( $V_{DD} = 12V$ ).

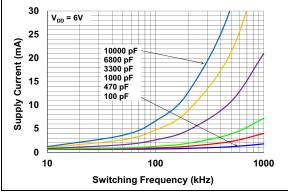


FIGURE 2-26: Supply Current vs. Frequency ( $V_{DD} = 6V$ ).

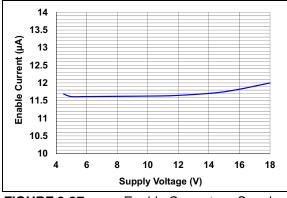


FIGURE 2-27: Enable Current vs. Supply Voltage.

NOTES:

# 3.0 PIN DESCRIPTIONS

The descriptions of the pins are listed in Table 3-1.

MCP14A	0453/4/5	Symbol	Description	
8L 2 x 3 TDFN	8L MSOP/SOIC	Symbol	Description	
1	1	ENA	Enable for Driver A	
2	2	INA	Input for Driver A	
3	3	GND	Device Ground	
4	4	INB	Input for Driver B	
5	5	OUTB/OUTB	Push-Pull for Output B	
6	6	V <sub>DD</sub>	Supply Input Voltage	
7	7	OUTA/OUTA	Push-Pull for Output A	
8	8	ENB	Enable for Driver B	
EP		EP	Exposed Thermal Pad (GND)	

#### TABLE 3-1: PIN FUNCTION TABLE

# 3.1 <u>Output</u> Pins (OUTA/OUTA, OUTB/OUTB)

The outputs are CMOS push-pull circuits that are capable of sourcing and sinking 4.5A of peak current ( $V_{DD}$  = 18V). The low output impedance ensures the gate of the external MOSFET stays in the intended state, even during large transients. This output also has a reverse current latch-up rating of 500 mA.

# 3.2 Device Ground Pin (GND)

GND is the device return pin for the input and output stages. The GND pin should have a low-impedance connection to the bias supply source return. When the capacitive load is being discharged, high peak currents will flow through the ground pin.

# 3.3 Device Enable Pins (ENA, ENB)

The MOSFET driver device enable pins are high-impedance inputs featuring low threshold levels. The enable inputs also have hysteresis between the high and low input levels, allowing them to be driven from slow rising and falling signals, and to provide noise immunity. Driving the enable pins below the threshold will disable the corresponding output of the device, pulling OUT/OUT low, regardless of the status of the input pin. Driving the enable pins above the threshold allows normal operation of the OUT/OUT pin based on the status of the input pin. The enable pins utilize internal pull-up resistors, allowing the pins to be left floating for standard driver operation.

# 3.4 Control Input Pins (INA, INB)

The MOSFET driver control inputs are high-impedance inputs featuring low threshold levels. The inputs also have hysteresis between the high and low input levels, allowing them to be driven from slow rising and falling signals, and to provide noise immunity.

# 3.5 Supply Input Pin (V<sub>DD</sub>)

 $V_{DD}$  is the bias supply input for the MOSFET driver and has a voltage range of 4.5V to 18V. This input must be decoupled to ground with a local capacitor. This bypass capacitor provides a localized low-impedance path for the peak currents that are provided to the load.

# 3.6 Exposed Metal Pad Pin (EP)

The exposed metal pad of the TDFN package is internally connected to GND. Therefore, this pad should be connected to a Ground plane to aid in heat removal from the package.

NOTES:

# 4.0 APPLICATION INFORMATION

# 4.1 General Information

MOSFET drivers are high-speed, high-current devices that are intended to source/sink high-peak currents to charge/discharge the gate capacitance of external MOSFETs or Insulated-Gate Bipolar Transistors (IGBTs). In high-frequency switching power supplies, the Pulse-Width Modulation (PWM) controller may not have the drive capability to directly drive the power MOSFET. A MOSFET driver such as the MCP14A0453/4/5 family can be used to provide additional source/sink current capability.

# 4.2 MOSFET Driver Timing

The ability of a MOSFET driver to transition from a fully-off state to a fully-on state is characterized by the driver's rise time ( $t_R$ ), fall time ( $t_F$ ) and propagation delays ( $t_{D1}$  and  $t_{D2}$ ). Figure 4-1 and Figure 4-2 show the test circuit and timing waveform used to verify the MCP14A0453/4/5 timing.

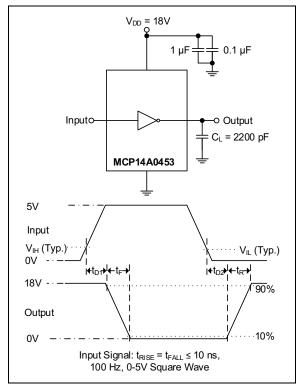
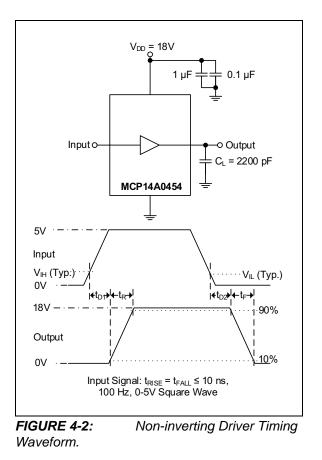


FIGURE 4-1:Inverting Driver TimingWaveform.



# 4.3 Enable Function

The enable pins (EN A, EN B) provide additional control of the output pins (OUT). These pins are active-high and are internally pulled up to  $V_{DD}$  so that the pins can be left floating to provide standard MOSFET driver operation.

When the enable pin input voltages are above the enable pin high-voltage threshold ( $V_{EN\_H}$ ), the corresponding output is enabled and allowed to react to the status of the input pin. However, when the voltage applied to the enable pins falls below the low threshold voltage ( $V_{EN\_L}$ ), the driver's corresponding output is disabled and doesn't respond to changes in the status of the input pins. When the driver is disabled, the output is pulled down to a low state. Refer to Table 4-1 for the enable pin are similar to the threshold voltage levels for the enable pin are similar to the threshold voltage levels of the input pin and are TTL compatible. Hysteresis is provided to help increase the noise immunity of the enable function, avoiding false triggers of the enable signal during driver switching.

There are propagation delays associated with the driver receiving an enable signal and the output reacting. These propagation delays,  $t_{D3}$  and  $t_{D4}$ , are graphically represented in Figure 4-3.

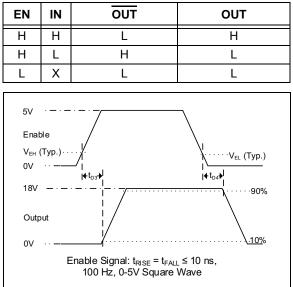


TABLE 4-1:ENABLE PIN LOGIC

FIGURE 4-3: Enable Timing Waveform.

### 4.4 Decoupling Capacitors

Careful Printed Circuit Board (PCB) layout and decoupling capacitors are required when using power MOSFET drivers. Large current is required to charge and discharge capacitive loads quickly. For example, approximately 720 mA are needed to charge a 1000 pF load with 18V in 25 ns.

To operate the MOSFET driver over a wide frequency range with low supply impedance, it is recommended to place 1.0  $\mu$ F and 0.1  $\mu$ F low ESR ceramic capacitors in parallel between the driver  $V_{DD}$  and GND. These capacitors should be placed close to the driver to minimize circuit board parasitics and provide a local source for the required current.

#### 4.5 PCB Layout Considerations

Proper PCB layout is important in high-current, fastswitching circuits to provide proper device operation and robustness of design. Improper component placement may cause errant switching, excessive voltage ringing or circuit latch-up. The PCB trace loop length and inductance should be minimized by the use of ground planes or traces under the MOSFET gate drive signal. Separate analog and power grounds and local driver decoupling should also be used.

Placing a ground plane beneath the MCP14A0453/4/5 devices will help as a radiated noise shield, as well as providing some heat sinking for power dissipated within the device.

### 4.6 **Power Dissipation**

The total internal power dissipation in a MOSFET driver is the summation of three separate power dissipation elements, as shown in Equation 4-1.

#### **EQUATION 4-1:**

$$P_{T} = P_{L} + P_{Q} + P_{CC}$$
Where:  

$$P_{T} = \text{Total power dissipation}$$

$$P_{L} = \text{Load power dissipation}$$

$$P_{Q} = \text{Quiescent power dissipation}$$

$$P_{CC} = \text{Operating power dissipation}$$

#### 4.6.1 CAPACITIVE LOAD DISSIPATION

The power dissipation caused by a capacitive load is a direct function of the frequency, total capacitive load and supply voltage. The power lost in the MOSFET driver for a complete charging and discharging cycle of a MOSFET is shown in Equation 4-2.

#### **EQUATION 4-2:**

$$P_L = f \times C_T \times V_{DD}^2$$

Where:

f = Switching frequency
 C<sub>T</sub> = Total load capacitance
 V<sub>DD</sub> = MOSFET driver supply voltage

# 4.6.2 QUIESCENT POWER DISSIPATION

The power dissipation associated with the quiescent current draw depends on the state of the Input and Enable pins. See **Section 1.0 "Electrical Characteristics"** for typical quiescent current draw values in different operating states. The quiescent power dissipation is shown in Equation 4-3.

#### **EQUATION 4-3:**

$$P_Q = (I_{QH} \times D + I_{QL} \times (1 - D)) \times V_{DD}$$

Where:

$$I_{QL}$$
 = Quiescent current in the Low state

#### 4.6.3 OPERATING POWER DISSIPATION

The operating power dissipation occurs each time the MOSFET driver output transitions because, for a very short period of time, both MOSFETs in the output stage are on simultaneously. This cross-conduction current leads to a power dissipation described in Equation 4-4.

 $P_{CC} = V_{DD} \times I_{CO}$ 

#### **EQUATION 4-4:**

Where:

I<sub>CO</sub> = Crossover Current

V<sub>DD</sub> = MOSFET driver supply voltage

NOTES:

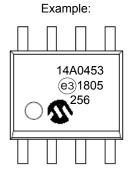
# 5.0 PACKAGING INFORMATION

# 5.1 Package Marking Information



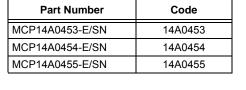
	1
Part Number	Code
MCP14A0453-E/MS	A0453
MCP14A0454-E/MS	A0454
MCP14A0455-E/MS	A0455





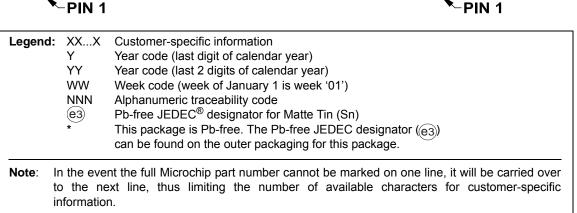
# 8-Lead TDFN







Example:



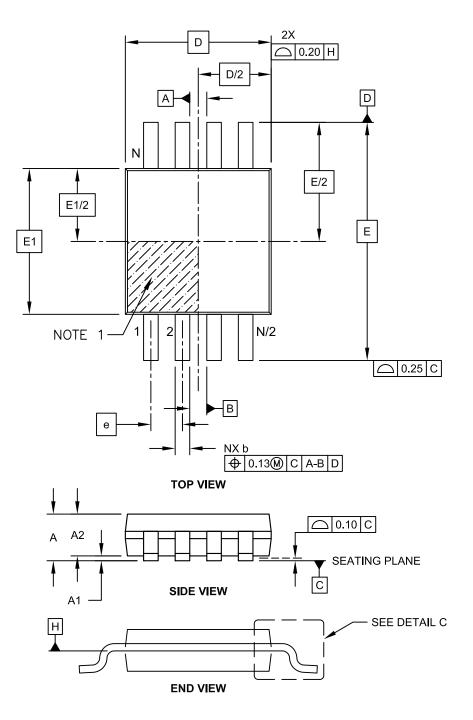
8-Lead SOIC

XXXXYYWW



# 8-Lead Plastic Micro Small Outline Package (MS) [MSOP]

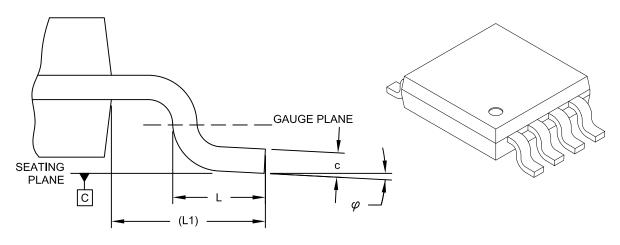
**Note:** For the most current package drawings, please see the Microchip Packaging Specification located at http://www.microchip.com/packaging



Microchip Technology Drawing C04-111C Sheet 1 of 2

#### 8-Lead Plastic Micro Small Outline Package (MS) [MSOP]

**Note:** For the most current package drawings, please see the Microchip Packaging Specification located at http://www.microchip.com/packaging



DETAIL C

	N	<b>ILLIMETER</b>	S	
Dimension	Dimension Limits		NOM	MAX
Number of Pins	N		8	
Pitch	е		0.65 BSC	
Overall Height	A	-	-	1.10
Molded Package Thickness	A2	0.75	0.85	0.95
Standoff	A1	0.00	-	0.15
Overall Width	E	4.90 BSC		
Molded Package Width	E1	3.00 BSC		
Overall Length	D		3.00 BSC	
Foot Length	L	0.40	0.60	0.80
Footprint	L1	0.95 REF		
Foot Angle	φ	0°	-	8°
Lead Thickness	С	0.08	-	0.23
Lead Width	b	0.22	-	0.40

Notes:

1. Pin 1 visual index feature may vary, but must be located within the hatched area.

2. Dimensions D and E1 do not include mold flash or protrusions. Mold flash or

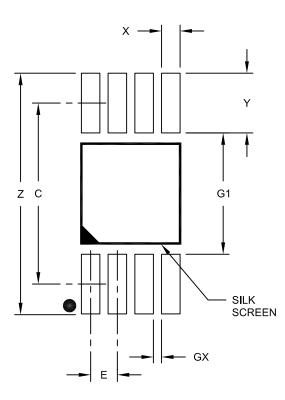
protrusions shall not exceed 0.15mm per side.

Dimensioning and tolerancing per ASME Y14.5M.
 BSC: Basic Dimension. Theoretically exact value shown without tolerances.
 REF: Reference Dimension, usually without tolerance, for information purposes only.

Microchip Technology Drawing C04-111C Sheet 2 of 2

8-Lead Plastic Micro Small Outline Package (MS) [MSOP]

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# RECOMMENDED LAND PATTERN

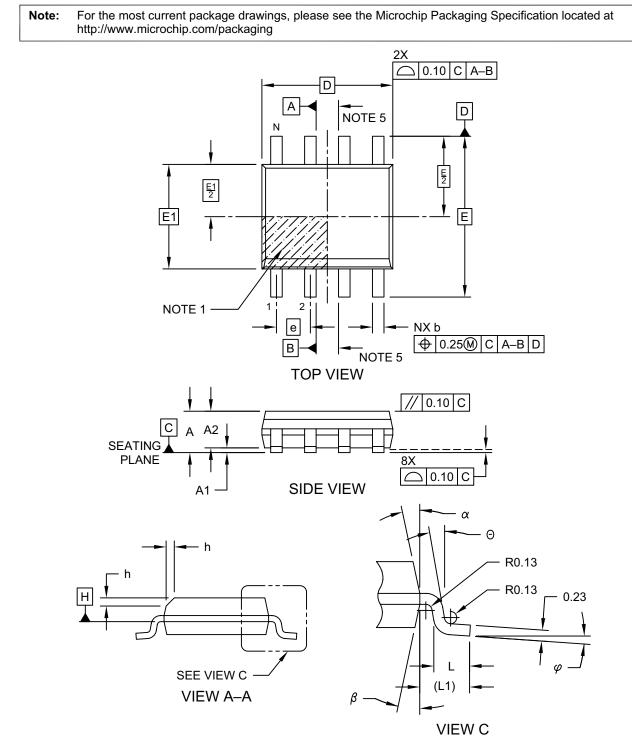
	Units	Ν	<b>MILLIMETER</b>	S
Dimensio	n Limits	MIN	NOM	MAX
Contact Pitch	E	0.65 BSC		
Contact Pad Spacing	С		4.40	
Overall Width	Z			5.85
Contact Pad Width (X8)	X1			0.45
Contact Pad Length (X8)	Y1			1.45
Distance Between Pads	G1	2.95		
Distance Between Pads	GX	0.20		

Notes:

1. Dimensioning and tolerancing per ASME Y14.5M

BSC: Basic Dimension. Theoretically exact value shown without tolerances.

Microchip Technology Drawing No. C04-2111A

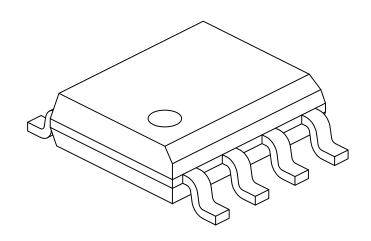


## 8-Lead Plastic Small Outline (SN) - Narrow, 3.90 mm (.150 In.) Body [SOIC]

Microchip Technology Drawing No. C04-057-SN Rev D Sheet 1 of 2

# 8-Lead Plastic Small Outline (SN) - Narrow, 3.90 mm (.150 In.) Body [SOIC]

**Note:** For the most current package drawings, please see the Microchip Packaging Specification located at http://www.microchip.com/packaging



	MILLIMETERS			
Dimensior	Dimension Limits			MAX
Number of Pins	N		8	
Pitch	е		1.27 BSC	
Overall Height	Α	-	-	1.75
Molded Package Thickness	A2	1.25	-	-
Standoff §	A1	0.10	-	0.25
Overall Width	E	6.00 BSC		
Molded Package Width	E1	3.90 BSC		
Overall Length	D	4.90 BSC		
Chamfer (Optional)	h	0.25	-	0.50
Foot Length	L	0.40	-	1.27
Footprint	L1		1.04 REF	
Foot Angle	φ	0°	-	8°
Lead Thickness	С	0.17 - 0.25		
Lead Width	b	0.31	-	0.51
Mold Draft Angle Top	α	5° - 15°		
Mold Draft Angle Bottom	β	5°	-	15°

Notes:

1. Pin 1 visual index feature may vary, but must be located within the hatched area.

2. § Significant Characteristic

- 3. Dimensions D and E1 do not include mold flash or protrusions. Mold flash or protrusions shall not exceed 0.15mm per side.
- 4. Dimensioning and tolerancing per ASME Y14.5M

BSC: Basic Dimension. Theoretically exact value shown without tolerances.

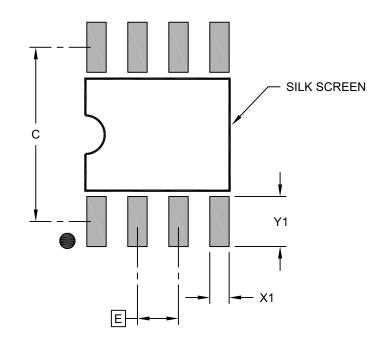
REF: Reference Dimension, usually without tolerance, for information purposes only.

5. Datums A & B to be determined at Datum H.

Microchip Technology Drawing No. C04-057-SN Rev D Sheet 2 of 2

# 8-Lead Plastic Small Outline (SN) - Narrow, 3.90 mm Body [SOIC]

**Note:** For the most current package drawings, please see the Microchip Packaging Specification located at http://www.microchip.com/packaging



# RECOMMENDED LAND PATTERN

	Ν	<b>/ILLIMETER</b>	S	
Dimension Limits		MIN	NOM	MAX
Contact Pitch	E		1.27 BSC	
Contact Pad Spacing	С		5.40	
Contact Pad Width (X8)	X1			0.60
Contact Pad Length (X8)	Y1			1.55

Notes:

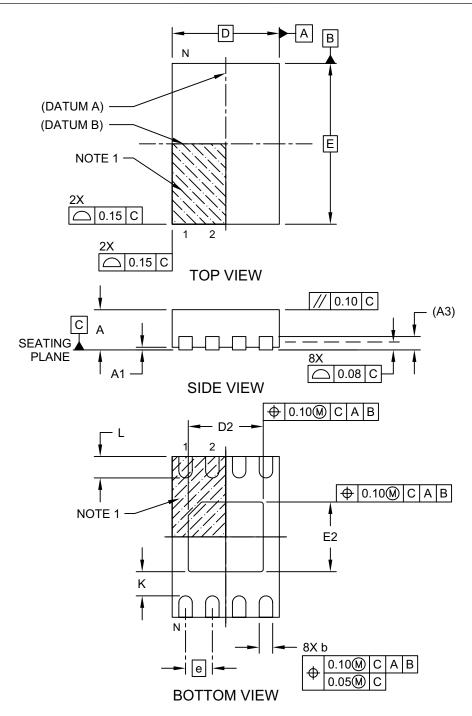
1. Dimensioning and tolerancing per ASME Y14.5M

BSC: Basic Dimension. Theoretically exact value shown without tolerances.

Microchip Technology Drawing C04-2057-SN Rev B

# 8-Lead Plastic Dual Flat, No Lead Package (MNY) – 2x3x0.8 mm Body [TDFN] With 1.4x1.3 mm Exposed Pad (JEDEC Package type WDFN)

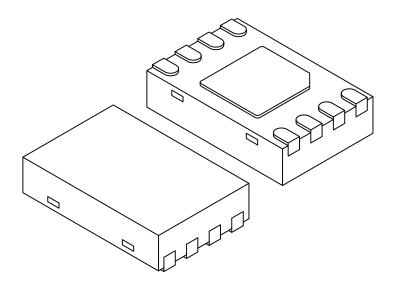
**Note:** For the most current package drawings, please see the Microchip Packaging Specification located at http://www.microchip.com/packaging



Microchip Technology Drawing No. C04-129-MNY Rev E Sheet 1 of 2

### 8-Lead Plastic Dual Flat, No Lead Package (MNY) – 2x3x0.8 mm Body [TDFN] With 1.4x1.3 mm Exposed Pad (JEDEC Package type WDFN)

**Note:** For the most current package drawings, please see the Microchip Packaging Specification located at http://www.microchip.com/packaging



Units		MILLIMETERS		
Dimension Limits		MIN	NOM	MAX
Number of Pins	N	8		
Pitch	е	0.50 BSC		
Overall Height	Α	0.70	0.75	0.80
Standoff	A1	0.00	0.02	0.05
Contact Thickness	A3	0.20 REF		
Overall Length	D	2.00 BSC		
Overall Width	Е	3.00 BSC		
Exposed Pad Length	D2	1.35	1.40	1.45
Exposed Pad Width	E2	1.25	1.30	1.35
Contact Width	b	0.20	0.25	0.30
Contact Length	L	0.25	0.30	0.45
Contact-to-Exposed Pad	К	0.20	-	-

#### Notes:

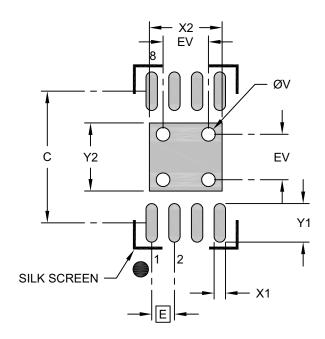
- 1. Pin 1 visual index feature may vary, but must be located within the hatched area.
- 2. Package may have one or more exposed tie bars at ends.
- 3. Package is saw singulated
- 4. Dimensioning and tolerancing per ASME Y14.5M

BSC: Basic Dimension. Theoretically exact value shown without tolerances. REF: Reference Dimension, usually without tolerance, for information purposes only.

Microchip Technology Drawing No. C04-129-MNY Rev E Sheet 2 of 2

# 8-Lead Plastic Dual Flat, No Lead Package (MNY) – 2x3x0.8 mm Body [TDFN] With 1.4x1.3 mm Exposed Pad (JEDEC Package type WDFN)

**Note:** For the most current package drawings, please see the Microchip Packaging Specification located at http://www.microchip.com/packaging



# RECOMMENDED LAND PATTERN

Units		MILLIMETERS		
Dimension Limits		MIN	NOM	MAX
Contact Pitch	E	0.50 BSC		
Optional Center Pad Width	X2			1.60
Optional Center Pad Length	Y2			1.50
Contact Pad Spacing	С		2.90	
Contact Pad Width (X8)	X1			0.25
Contact Pad Length (X8)	Y1			0.85
Thermal Via Diameter	V		0.30	
Thermal Via Pitch	EV		1.00	

Notes:

1. Dimensioning and tolerancing per ASME Y14.5M

BSC: Basic Dimension. Theoretically exact value shown without tolerances.

2. For best soldering results, thermal vias, if used, should be filled or tented to avoid solder loss during reflow process

Microchip Technology Drawing No. C04-129-MNY Rev. B

# APPENDIX A: REVISION HISTORY

# Revision A (March 2018)

• Original Release of this Document.

NOTES:

# **PRODUCT IDENTIFICATION SYSTEM**

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PART NO. [X] <sup>(</sup> Device Tape and	<sup>1)</sup> <u>–X /XX</u> I Reel Temperature Package Range	Examples: a) MCP14A0453T-E/MS: Tape and Reel, Extended temperature, 8LD MSOP package
Device:	MCP14A0453: High-Speed MOSFET Driver MCP14A0453T: High-Speed MOSFET Driver (Tape and Reel) MCP14A0454: High-Speed MOSFET Driver MCP14A0454T: High-Speed MOSFET Driver (Tape and Reel) MCP14A0455: High-Speed MOSFET Driver MCP14A0455T: High-Speed MOSFET Driver (Tape and Reel)	<ul> <li>b) MCP14A0454T-E/SN: Tape and Reel, Extended temperature, 8LD SOIC package</li> <li>c) MCP14A0455T-E/MNY: Tape and Reel Extended temperature, 8LD TDFN package</li> </ul>
Temperature Range: Package:	E = -40°C to +125°C (Extended) MS = Plastic Micro Small Outline Package (MSOP),8-lead SN = Plastic Small Outline Package (SOIC), 8-lead MNY = Plastic Dual Flat, No Lead Package (TDFN), 8-lead	Note 1: Tape and Reel identifier only appears in the catalog part number description. This identifier is used for ordering purposes and is not printed on the device package. Check with your Microchip Sales Office for package availability with the Tape and Reel option.

NOTES:

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